

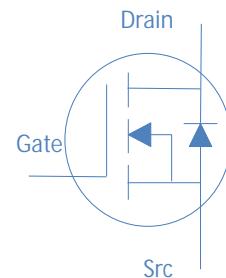
30V N-Ch Power MOSFET
Feature

High Speed Power Switching, Logic Level
 Enhanced Avalanche Ruggedness
 100% UIS Tested, 100% R_g Tested
 Lead Free, Halogen Free

V_{DS}	30	V
$R_{DS(on),typ}$	$V_{GS}=10V$	19 mΩ
$R_{DS(on),typ}$	$V_{GS}=4.5V$	30 mΩ
I_D (Silicon Limited)	6	A

Application

Hard Switching and High Speed Circuit
 DC/DC in Telecoms and Industrial

SOT-23


Part Number	Package	Marking
HTJ270N03	SOT23	14

Absolute Maximum Ratings at $T_J=25^\circ C$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	$T_A=25^\circ C$	6	A
		$T_A=70^\circ C$	4	
Drain to Source Voltage	V_{DS}	-	30	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	24	A
Power Dissipation	P_D	$T_A=25^\circ C$	1.25	W
Operating and Storage Temperature	T_J, T		-55 to 150	

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	100	/W

Electrical Characteristics at $T_J=25^\circ\text{C}$ (unless otherwise specified)
Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$	30	-	-	V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}, I_D=250\mu\text{A}$	1	1.7	3.0	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=24\text{V}, T_j=25^\circ\text{C}$	-	-	1	μA
		$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=20\text{V}, T_j=125^\circ\text{C}$	-	-	10	
Gate to Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Drain to Source on Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_D=6\text{A}$	-	19	27	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_D=5\text{A}$	-	30	40	
Transconductance	g_{fs}	$V_{\text{DS}}=5\text{V}, I_D=6\text{A}$	-	12	-	S

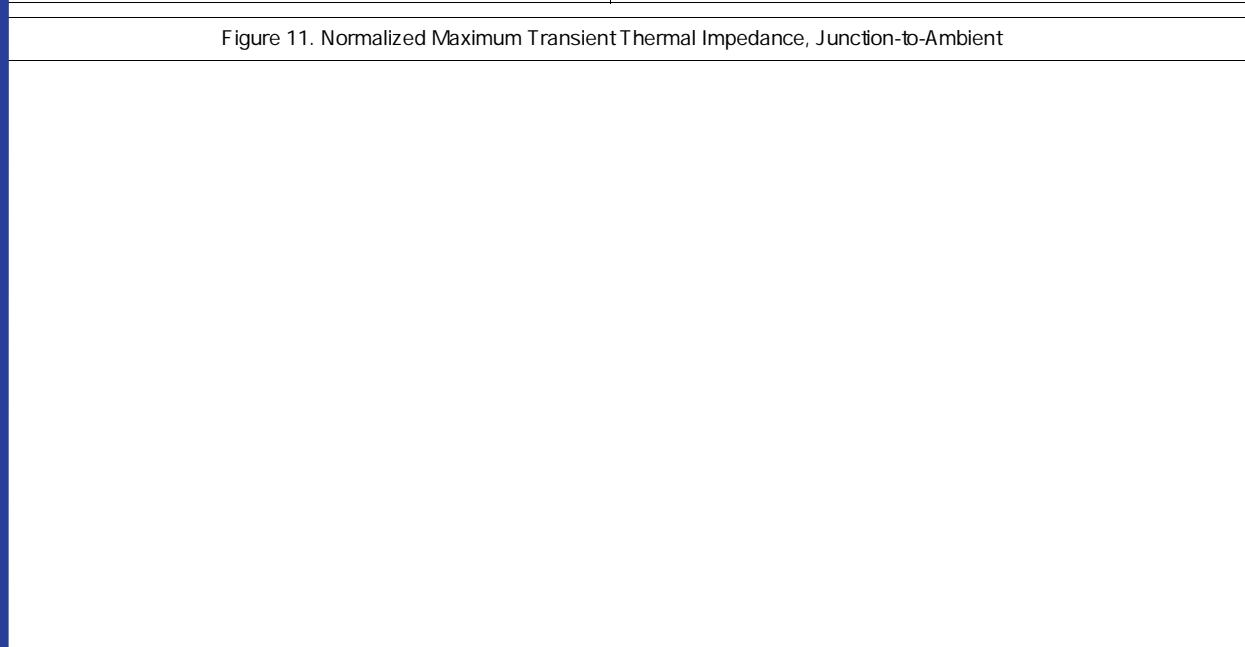
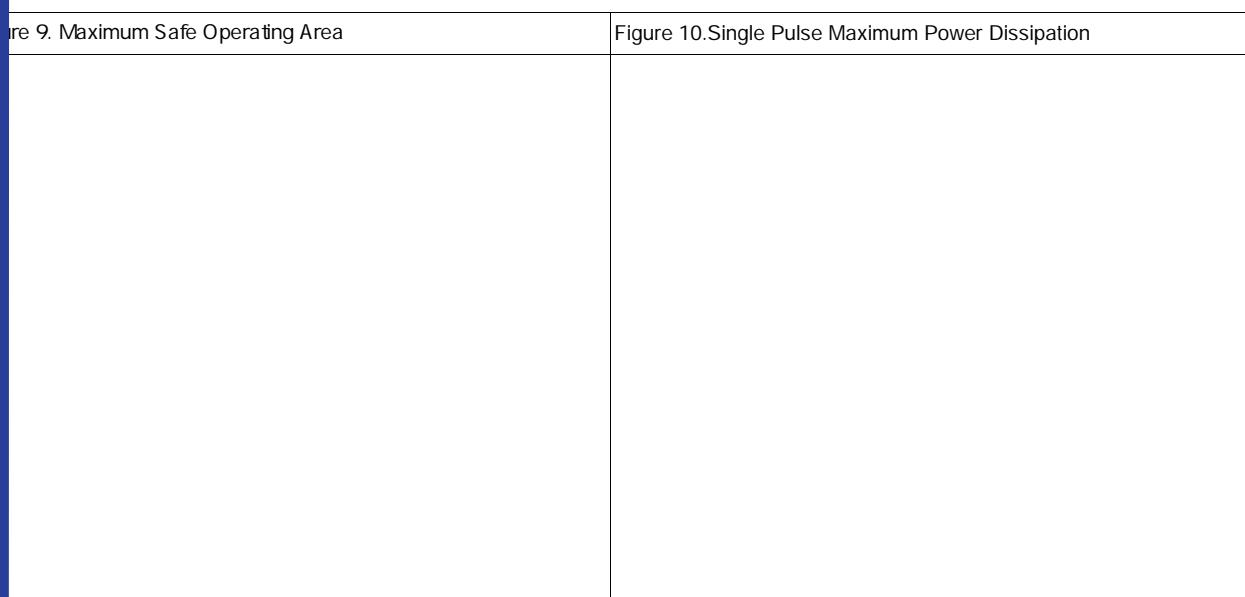
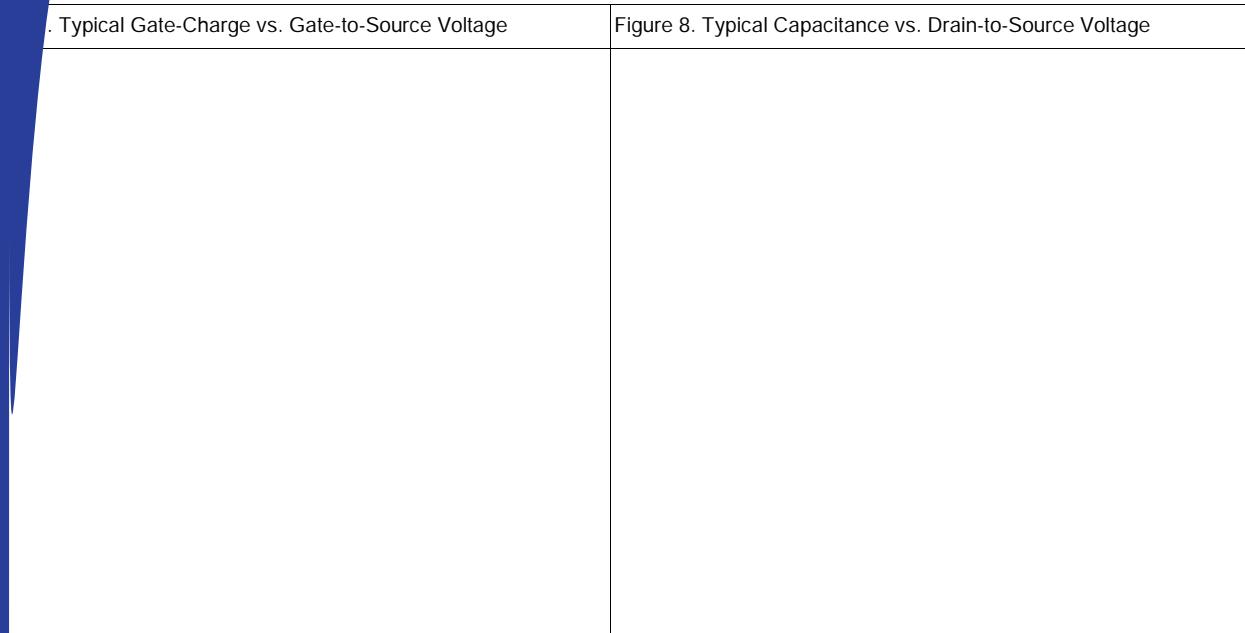
Dynamic Characteristics

Input Capacitance	C_{iss}	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=15\text{V}, f=1\text{MHz}$	-	522	-	pF
Output Capacitance	C_{oss}		-	105	-	
Reverse Transfer Capacitance	C_{rss}		-	82	-	
Total Gate Charge	Q_g	$V_{\text{DD}}=15\text{V}, I_D=6\text{A}, V_{\text{GS}}=10\text{V}$	-	10.9	-	nC
Gate to Source Charge	Q_{gs}		-	1.75	-	
Gate to Drain (Miller) Charge	Q_{gd}		-	3.4	-	
Turn on Delay Time	$t_{\text{d}(\text{on})}$		-	8	-	
Rise time	t_r	$V_{\text{DD}}=15\text{V}, I_D=1\text{A}, V_{\text{GS}}=10\text{V}, R_G=6\Omega$	-	7	-	ns
Turn off Delay Time	$t_{\text{d}(\text{off})}$		-	15	-	
Fall Time	t_f		-	10	-	

Reverse Diode Characteristics

Diode Forward Voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_F=2\text{A}$	-		1.2	V
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Fig 1. Typical Output Characteristics	Figure 2. On-Resistance vs. Gate-Source Voltage
Figure 3. On-Resistance vs. Drain Current and Gate Voltage	Figure 4. On-Resistance vs. Junction Temperature
Figure 5. Typical Transfer Characteristics	Figure 6. Typical Source-Drain Diode Forward Voltage





Inductive switching Test

Gate Charge Test

Uclamped Inductive Switching (UIS) Test

Diode Recovery Test



HES

Hochschule
für angewandte
Wissenschaften

St. Gallen

Winterthur

Zürich

Wettingen

Uster

Wädenswil

Wettingen

Wettingen